



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE

United States Patent and Trademark Office

Address: COMMISSIONER FOR PATENTS

P.O. Box 1450

Alexandria, Virginia 22313-1450

www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/715,555	11/19/2003	Scott Patrick Campbell	M4065.0812/P812-A	5068
24998 7590 08/18/2008 DICKSTEIN SHAPIRO LLP 1825 EYE STREET NW Washington, DC 20006-5403				
EXAMINER				
SELBY, GEVILL V				
ART UNIT		PAPER NUMBER		
2622				
MAIL DATE		DELIVERY MODE		
08/18/2008		PAPER		

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Response to Arguments

1. The Examiner would like to remind the applicant that an additional fee of \$420 is required for amending claims 34 and 37 to be independent in the amendment filed 7/29/08. There are now 8 independent claims and the applicant has only paid for three additional independent claims.

2. Applicant's arguments filed 7/29/08 have been fully considered but they are not persuasive. The applicant submits the prior art does not disclose all the limitations of claims 26, 27, 32, 33, 39, 40, and 44-47. The Examiner respectfully disagrees. The Kimura reference discloses an image sensor camera system with a solid state imaging device (see figure 2, element 20 and see column 3, lines 9-11). An example of one of the pixel of the solid state imaging device is pictured wherein it is inherent there are a plurality of pixels forming the imaging device, in order to capture the entire image. The solid state imaging device reads on an image sensor array having a plurality of sensors, said sensors operating to receive the optical data and integrate the data into electrical charge proportional to the amount of optical data collected with a particular period of time. The system includes a lens system formed of a well-shaped dug structure 21 formed in an interlayer insulating film 7, a high reflective index layer 8 form on the insulating layer 7, and a microlens 11, wherein the combination of elements reads on a lens system operatively coupled to the image sensor array and configured to carry and focus the optical data onto the image sensor array, said lens system including a plurality of lenses (microlens 11 and concave lens structure 21). The Kimura reference discloses a high refractive index layer 8 that is formed to the interlayer insulating film 7 so as to be contoured to the concave lensing structure 21 an covering across the entire solid state imaging device wherein the

top of the layer 8 is flattened like a plate (see column 3, lines 27-52); which reads on a cover plate, said cover plate contoured into a lensing structure that changes an imaging characteristic. The system includes a color filter 10 formed on the top surface of the index layer 8 through a passivation film 9 and the extending up from the layer 8 wherein the top of the color filter 10 allows for the mounting of the microlens 11 of the lensing system (see figure 2 and column 3, lines 52-53) which reads on a mounting structure extending from or forming a protrusion on an upper surface of said cover plate and adapted to secure said lens system to said cover plate above said lensing structure. Therefore, the Kimura reference discloses all the limitations of claims 27, 32, and 44 and the combination of Kimura and Iura discloses all the limitations of claims 26 and 46.

In regard to claim 39, Kimura discloses the well-shaped dug structure 21 becomes a concave lens structure (see column 3, lines 33-35) which reads on a concave lens portion.

In regard to claim 40, Kimura discloses microlens 11 which reads on a convex lens portion.

In regard to claims 45 and 47, Kimura discloses the well-shaped dug structure 21 becomes a concave lens structure in which light is refracted (see column 3, lines 33-35) which reads on a refractive lens.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to GEVELL SELBY whose telephone number is (571)272-7369. The examiner can normally be reached on 8:00 A.M. - 5:30 PM (every other Friday off).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Lin Ye can be reached on 571-272-7372. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

gvs